## CONTENT ADDRESSABLE MEMORY (CAM) DEVICES WITH DUAL-FUNCTION CHECK BIT CELLS THAT SUPPORT COLUMN REDUNDANCY AND CHECK BIT CELLS WITH REDUCED SUSCEPTIBILITY TO SOFT ERRORS

## Abstract of the Disclosure

Content addressable memory (CAM) devices include dual-function check bit cells that can operate as check bit cells to support error detection and correction (EDC) operations or as redundant CAM cells that support column redundancy. Dedicated check bit cells are also provided that have a reduced susceptibility to soft errors relative to adjacent CAM cells. The dedicated check bit cells may also be provided within a global mask cell sub-array to support correction of soft errors within global masks.

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